

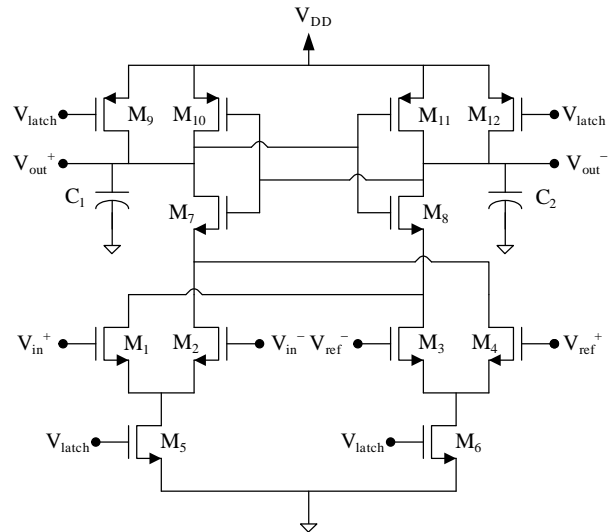
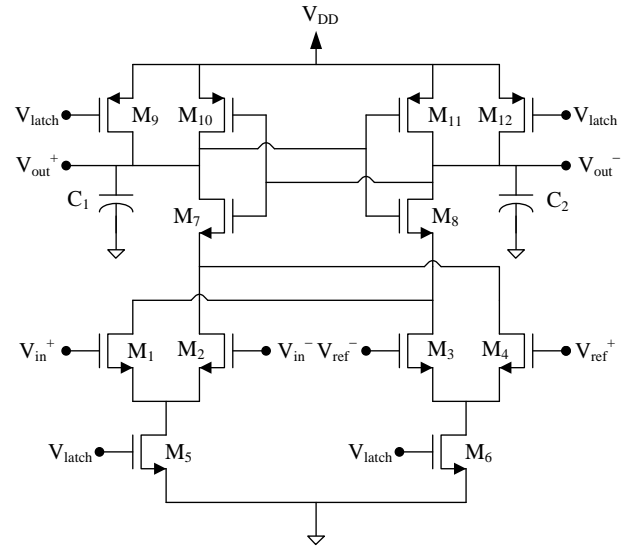
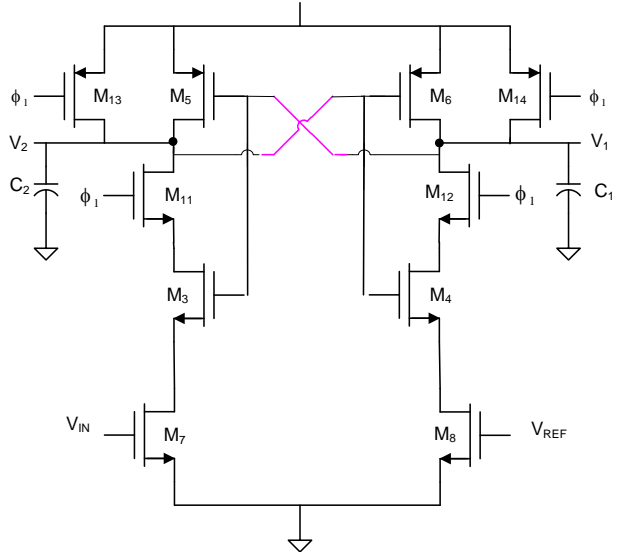
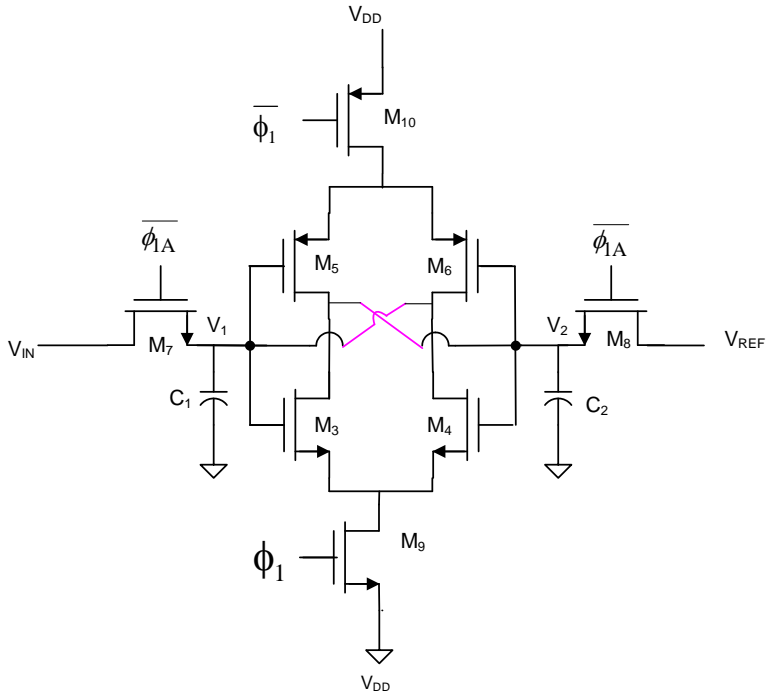
EE 505

Lecture 21

ADC Design

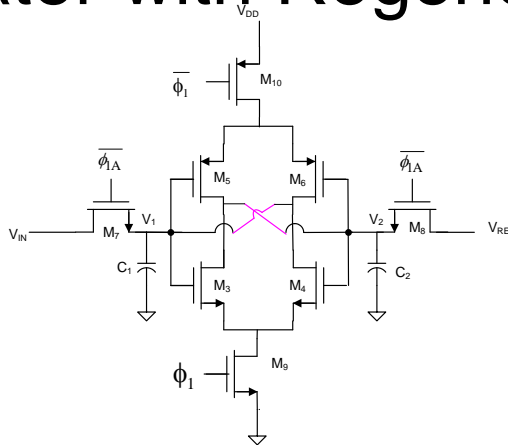
- The Flash ADC
- Comparators
- Interpolating ADCs

Review from Last Lecture

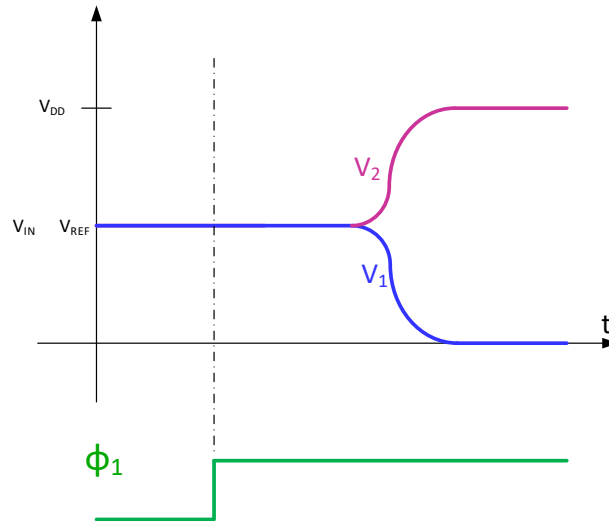
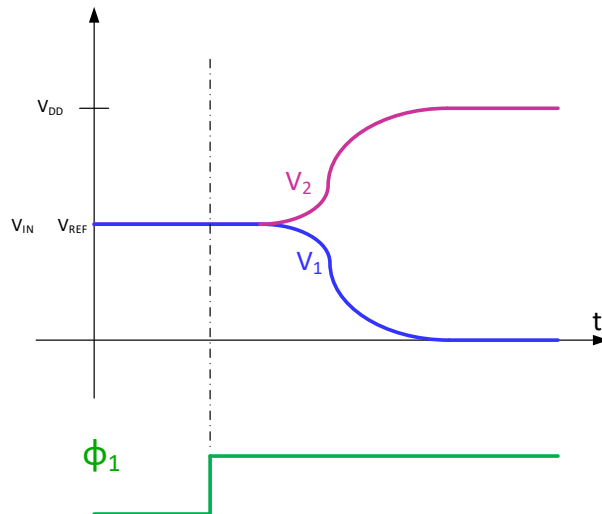


Review from Last Lecture

Clocked Comparator with Regenerative Feedback



when V_{IN} and V_{REF} close to each other

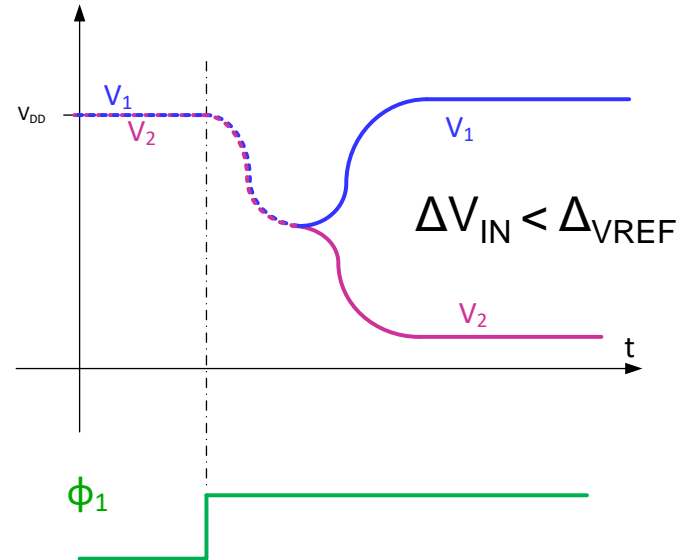
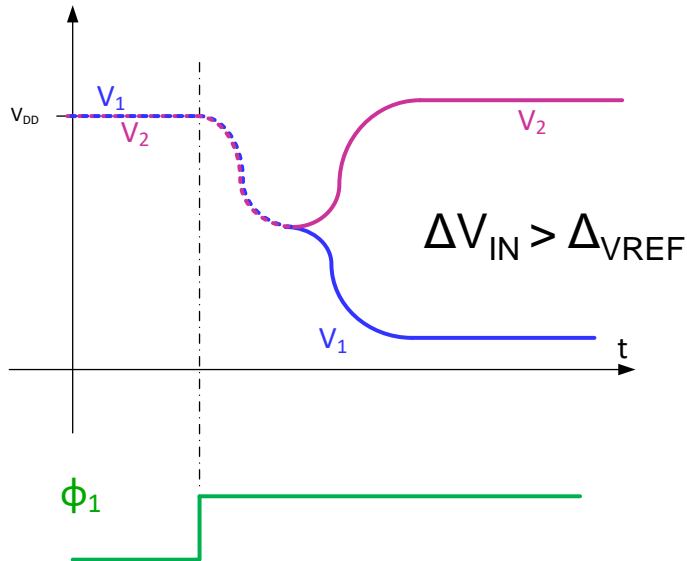


- decision delayed
- may stay in metastable state until after decision must be made
- vulnerable to making wrong decision due to offset or noise

Review from Last Lecture

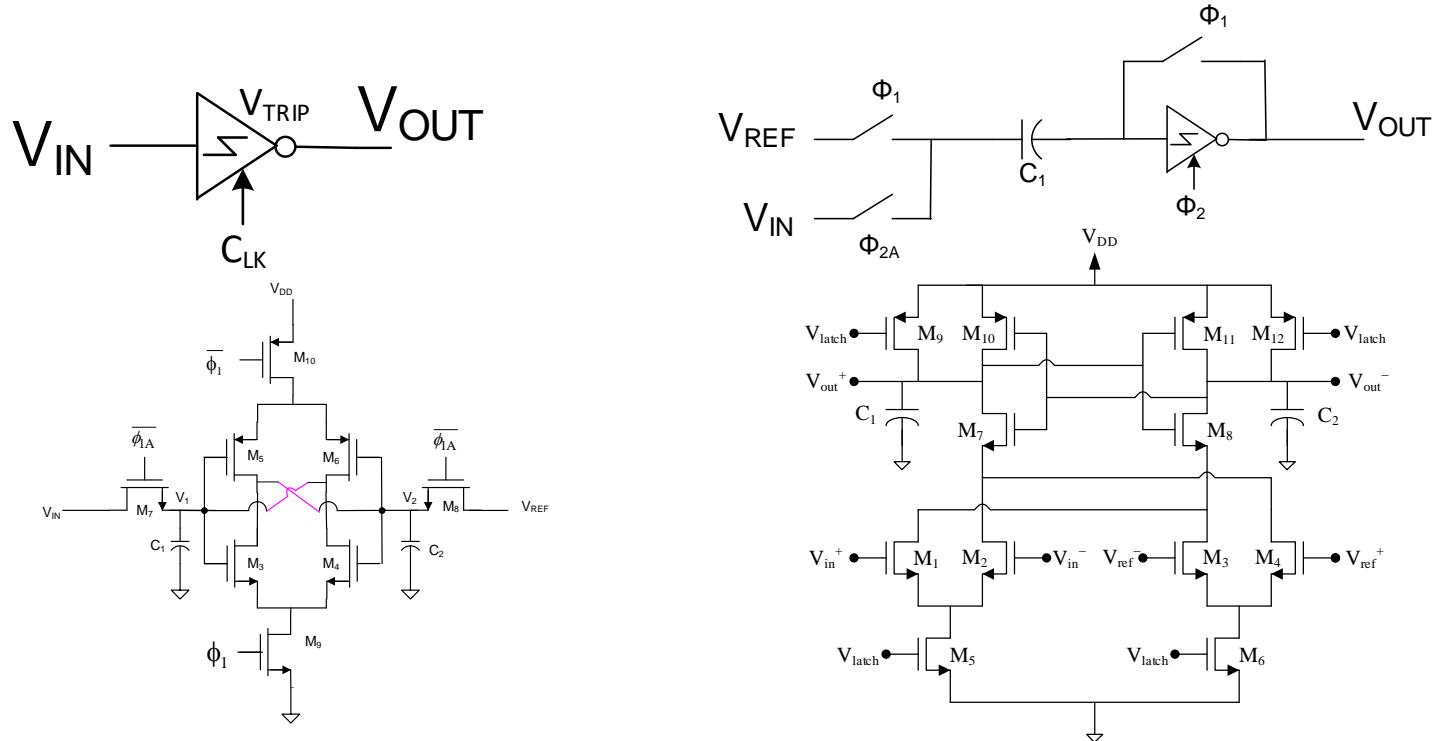


Ideal Responses



Review from Last Lecture

Where are poles of regenerative comparators located?

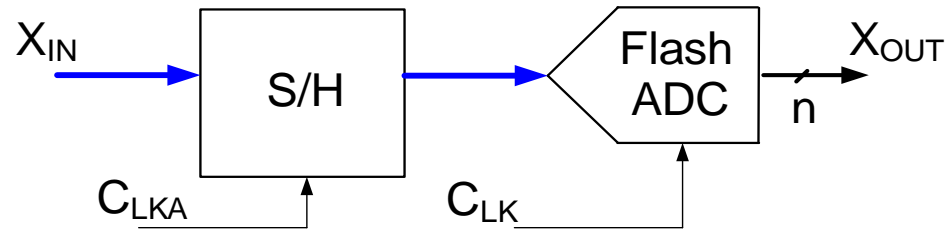


In RHP !

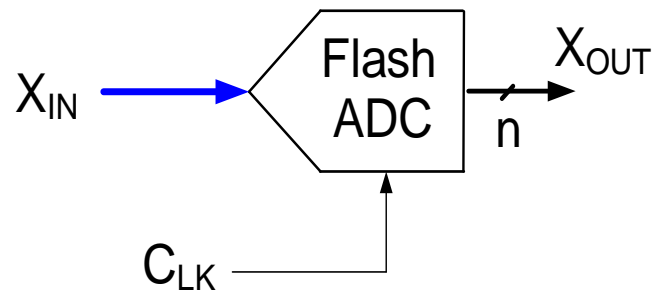
Is stability of concern?

No ! Want positive real axis poles (i.e. unstable circuit)
to force decision

Input change during conversion



Can we clock only the comparators in a Flash ADC thereby eliminating the S/H?

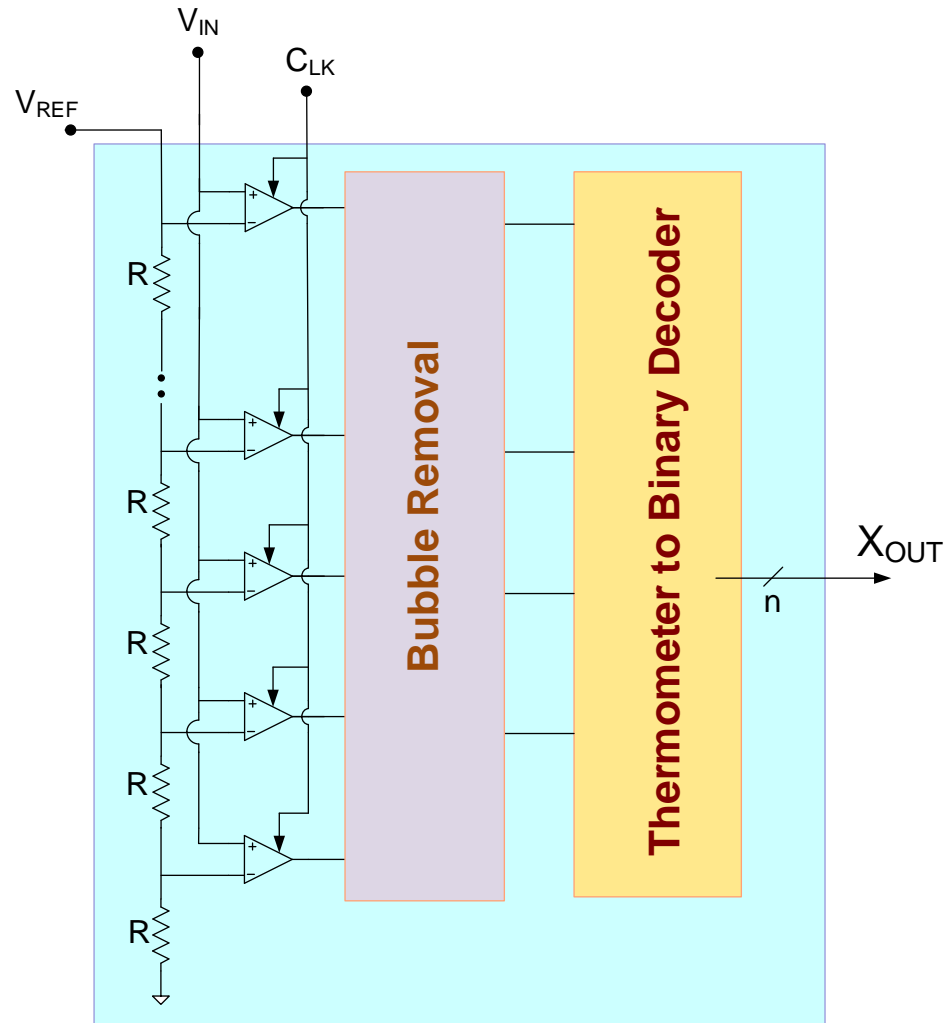


Clocking of Comparators Only

- Extremely tight requirements on CLK generator and Input propagation
- Clocking of pre-amps may not be easy to do
- Some switched-capacitor comparators may have inherent S/H of the input

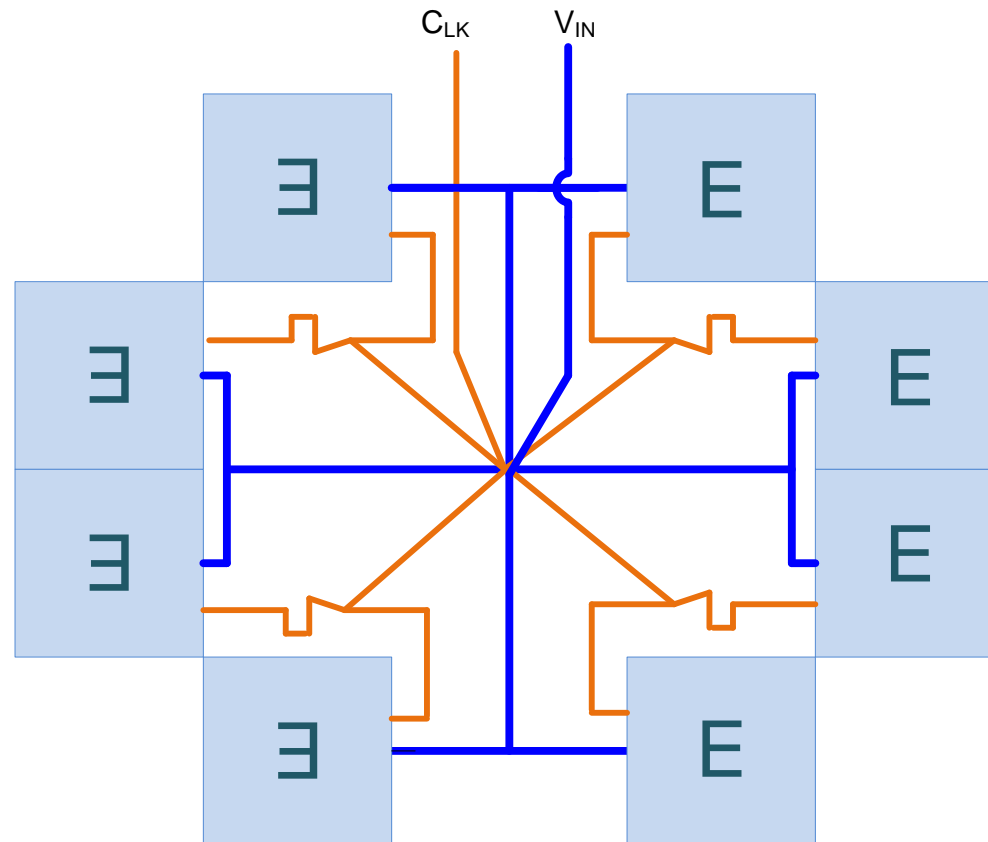
Input change during conversion

Clock of Comparators only in Flash ADC



Input change during conversion

Routing of Clock and Input is Critical

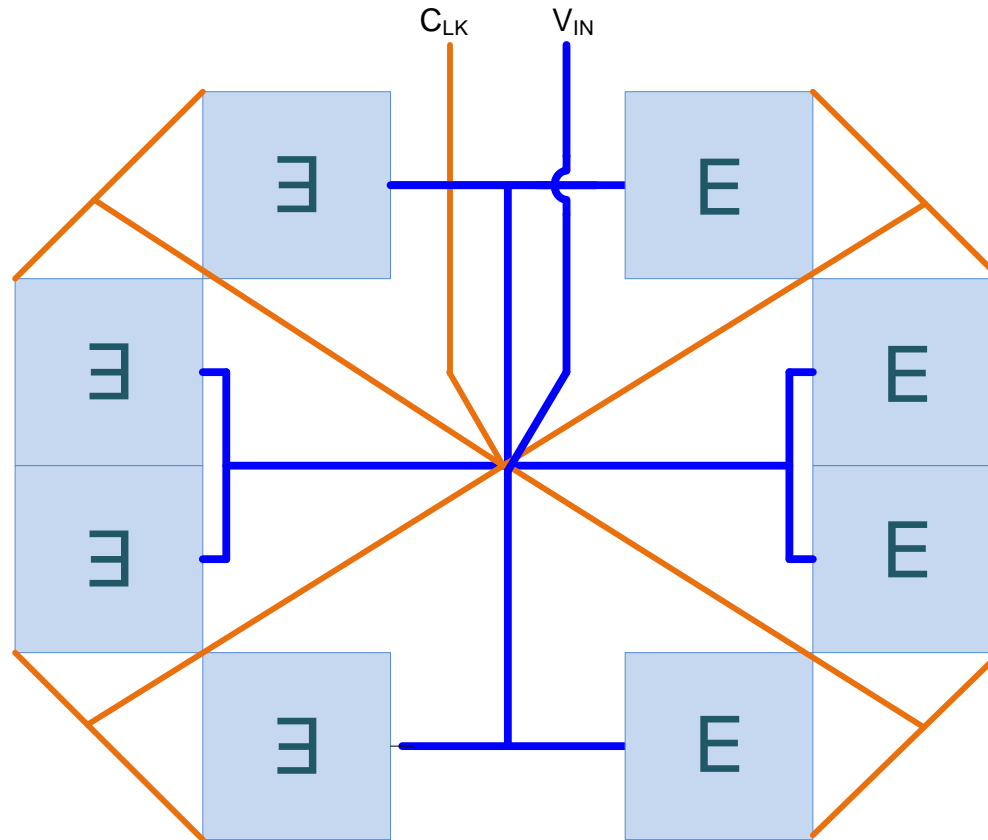


Symmetric Equal Path Length Layout

Path length of V_{IN} and C_{LK} need not be identical but convenient if they are
Have maintained minimal overlap of V_{IN} and C_{LK}

Input change during conversion

Routing of Clock and Input is Critical

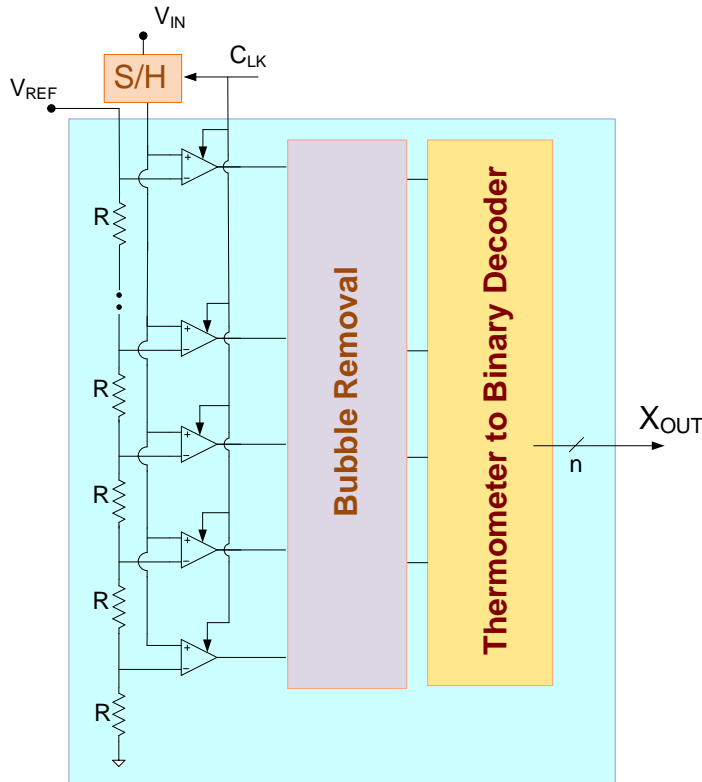


Symmetric Paths for V_{IN} and C_{LK}

Flash ADC

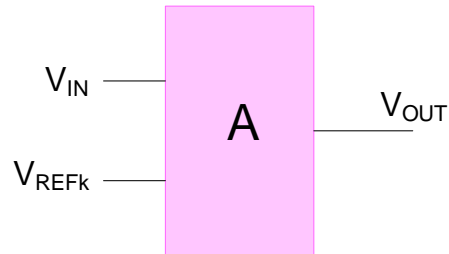
Basic structure has thermometer code at output

Performance Issues:



- + Very fast
- + Simple architecture
- + Instantaneous output
- ✓ Bubble vulnerability
- ✓ Input change during conversion
- ✓ Offset of comparators
- ✓ Number of components and area (for large n)
- ➡ Speed of comparators
- Loading of V_{REF} and V_{IN}
- Propagation of V_{IN} and Kickback
- Power dissipation (for large n)
- Layout of resistors
- Voltage and temperature dependence of R's
- Matching of R's

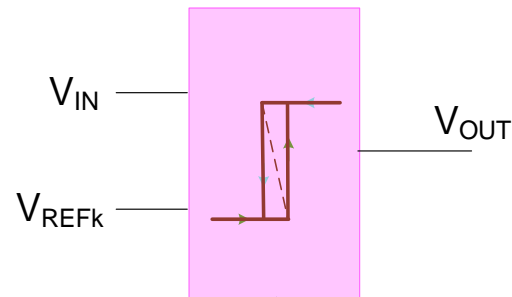
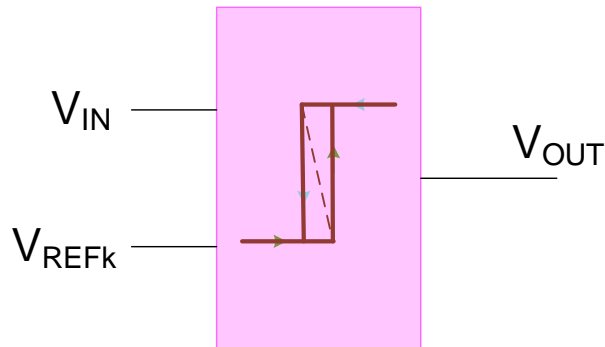
Speed of Comparators



Linear Amplifier as Comparator

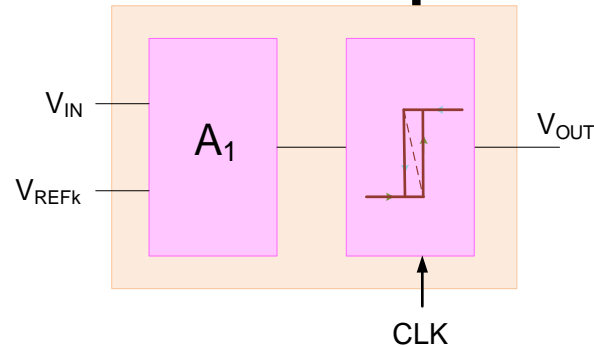
- Gain may be inadequate to generate Boolean output for some inputs (metastability)
- Common-mode input varies significantly with V_{REFk}

Regenerative Feedback Comparators



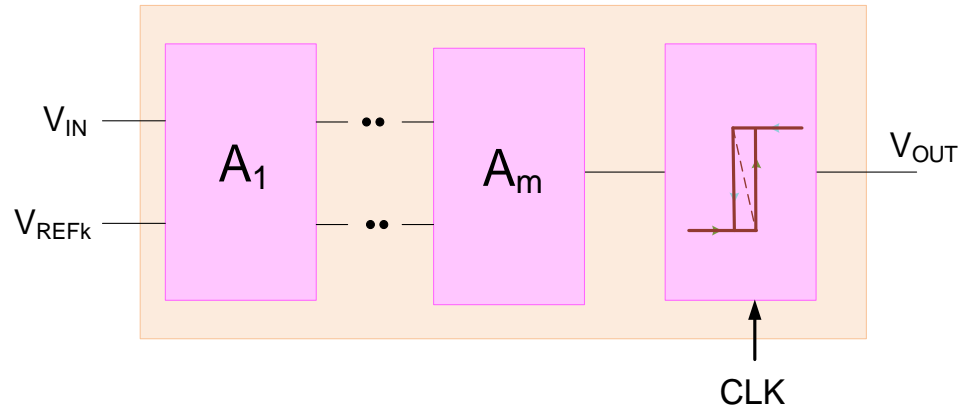
- Reduces (but does not eliminate) metastability concerns
- Common-mode input still varies with V_{REFk}
- Offset Voltage High
- C_{LK} can significantly improve speed
- C_{LK} can force operation on negative slope region thereby reducing hysteresis window-induced previous code dependence
- Kickback to Input of concern

Speed of Comparators



- Preamp often precedes regenerative stage
- Regenerative stage can be single-ended or differential
- Common-mode input to preamp still of concern
- Common-mode inputs of all regenerative stages can be the same
- Significant reduction in offset voltage possible
- Kickback to V_{IN} and V_{REFk} can be reduced

Speed of Comparators

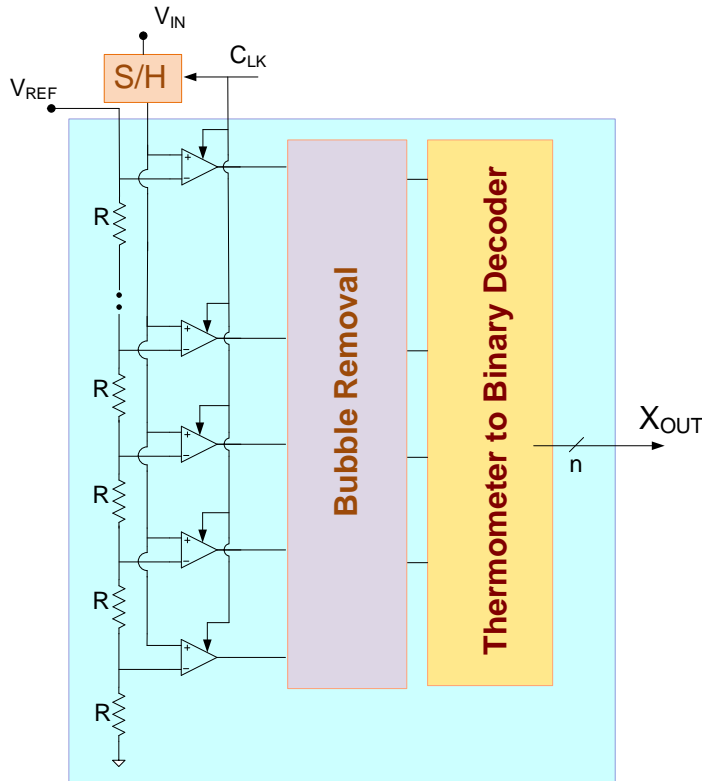


- Two or more stages of preamp gain often used
- Further reduces offset voltage and metastability concerns
- Number of stages can be selected to optimize speed and power
- Common-mode input in all stages after first can be the same

Flash ADC

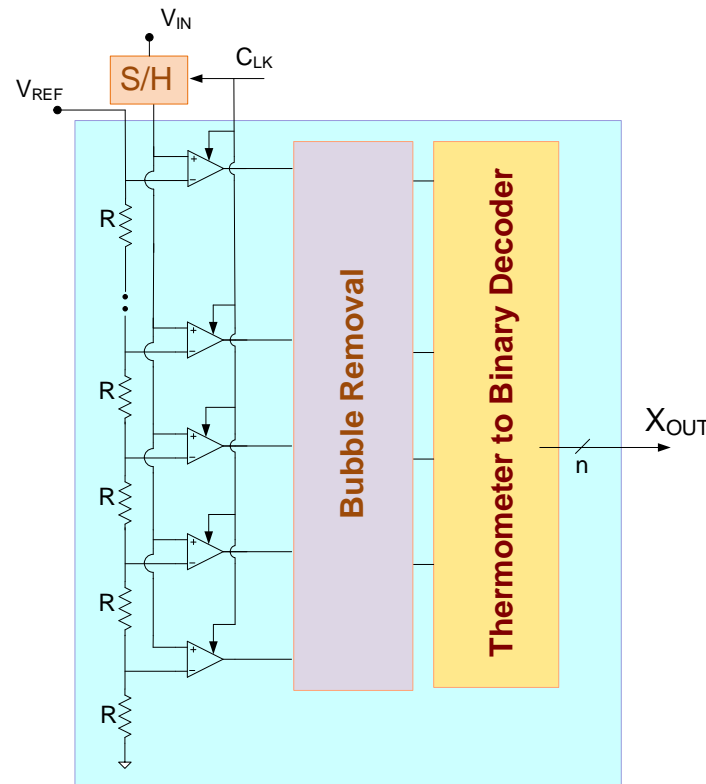
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Loading of V_{REF} and V_{IN}

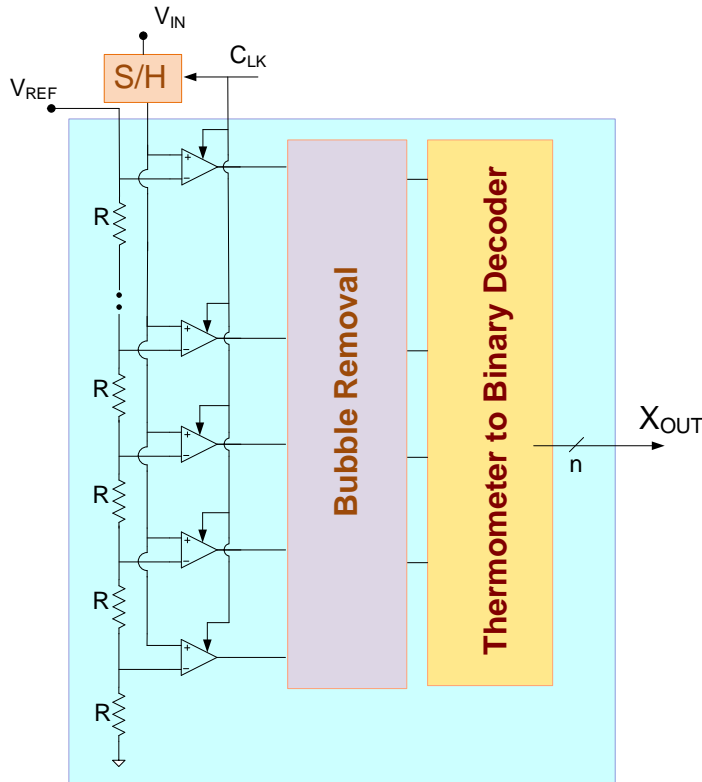


- Capacitive load on V_{IN} is large for large n
- Resistors in R-string small for fast recovery when V_{IN} changes
- Inductance on bonding leads for V_{REF} of concern if V_{REF} externally generated
- Output impedance must remain low at high frequencies if V_{REF} internally generated

Flash ADC

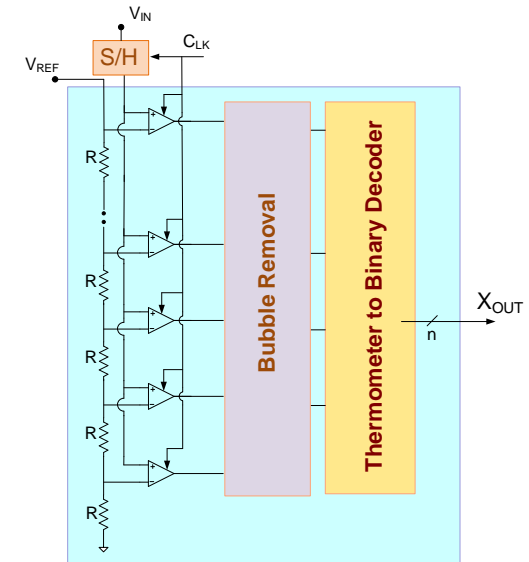
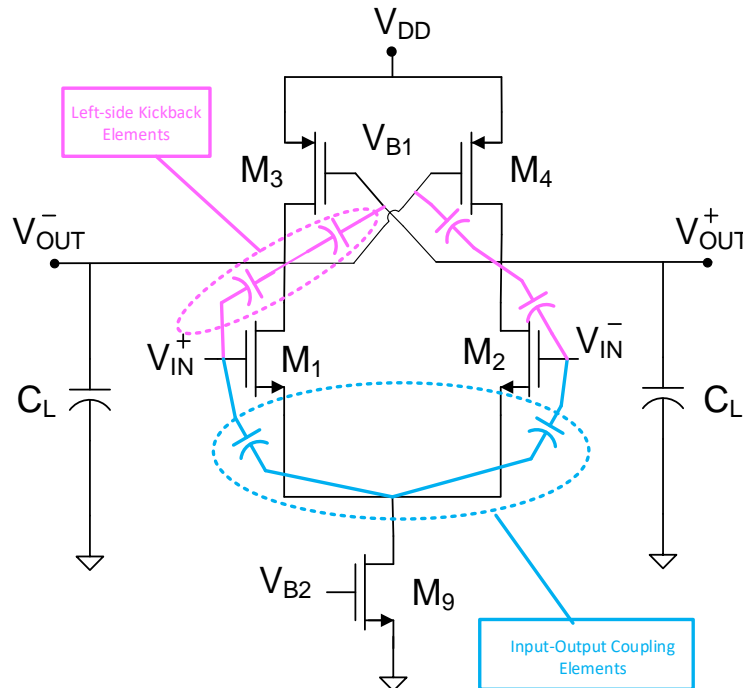
Basic structure has thermometer code at output

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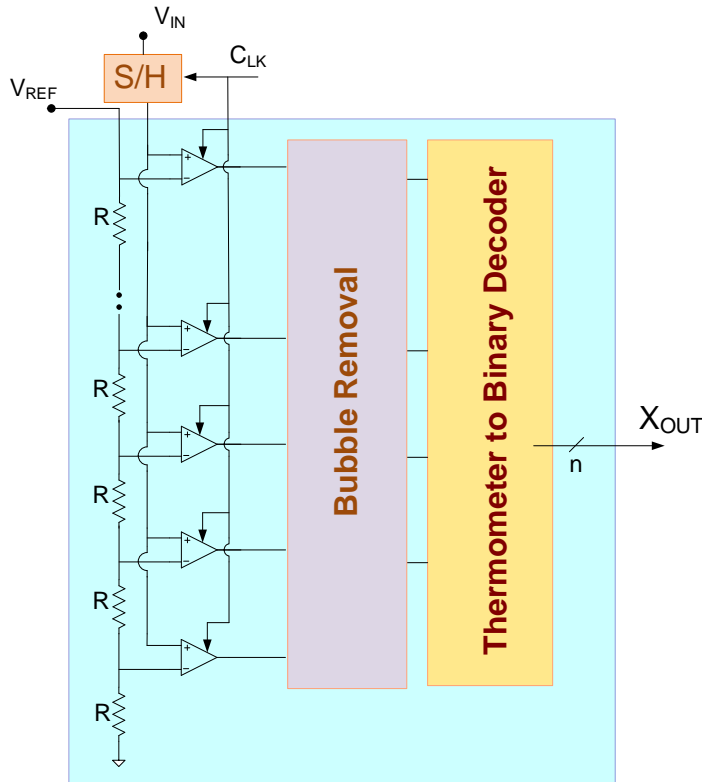
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Propagation of V_{IN} and Kickback



- Key decisions being made by comparators near 0-1 thermometer code transition
- Several comparators often changing states during each conversion introducing lots of kickback
- Kickback can be reduced by introducing preamp
- Input-output coupling on each comparator introduces large transients in R-string for large input changes
- Delay in V_{IN} propagating down string but introducing delay in clock can mitigate concern

Flash ADC



Basic structure has thermometer code at output

Performance Issues:

- + Very fast
- + Simple architecture
- + Instantaneous output

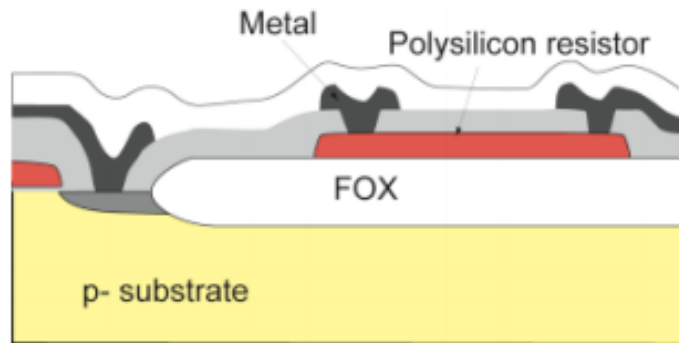
- ✓ Bubble vulnerability
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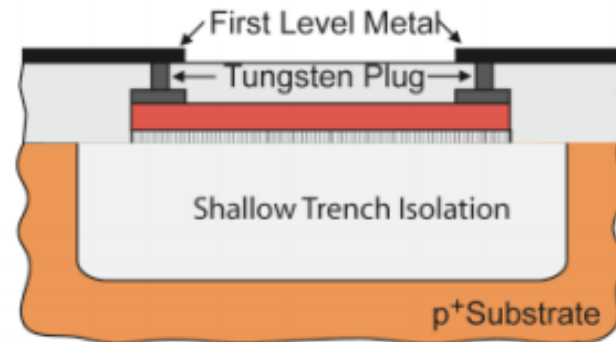
Voltage and temperature dependence of R's

From lecture notes of Phil Allen

Polysilicon Resistor



081027-04 Older LOCOS Technology

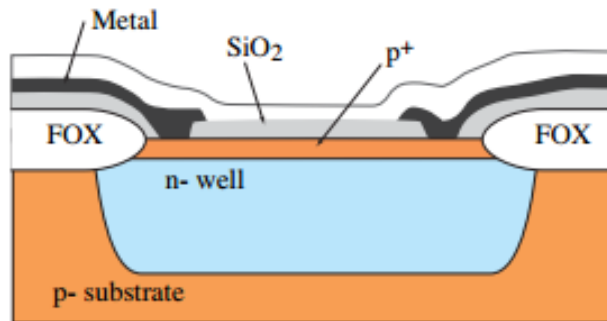


30-100 ohms/square (unshielded)
100-500 ohms/square (shielded)
Absolute accuracy = $\pm 3.0\%$
Relative accuracy = 2% ($5\ \mu\text{m}$)
Temperature coefficient = 500-1000 ppm/ $^{\circ}\text{C}$
Voltage coefficient $\approx 100\ \text{ppm/V}$

Voltage and temperature dependence of R's

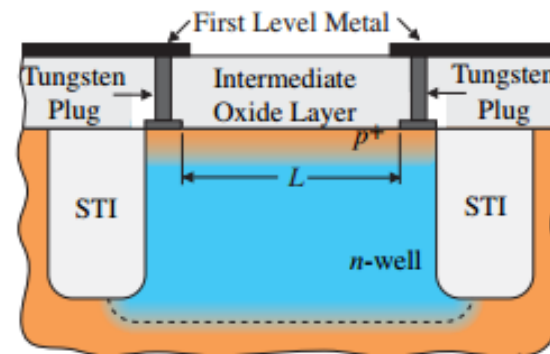
From lecture notes of Phil Allen

MOS Resistors - Source/Drain Resistor



060214-02

Older LOCOS Technology



Diffusion:

10-100 ohms/square

Absolute accuracy = $\pm 35\%$

Relative accuracy = 2% ($5\mu\text{m}$), 0.2% ($50\mu\text{m}$)

Temperature coefficient = $+1500 \text{ ppm}/^\circ\text{C}$

Voltage coefficient $\approx 200 \text{ ppm}/\text{V}$

Ion Implanted:

500-2000 ohms/square

Absolute accuracy = $\pm 15\%$

Relative accuracy = 2% ($5\mu\text{m}$), 0.15% ($50\mu\text{m}$)

Temperature coefficient = $+400 \text{ ppm}/^\circ\text{C}$

Voltage coefficient $\approx 800 \text{ ppm}/\text{V}$

Comments:

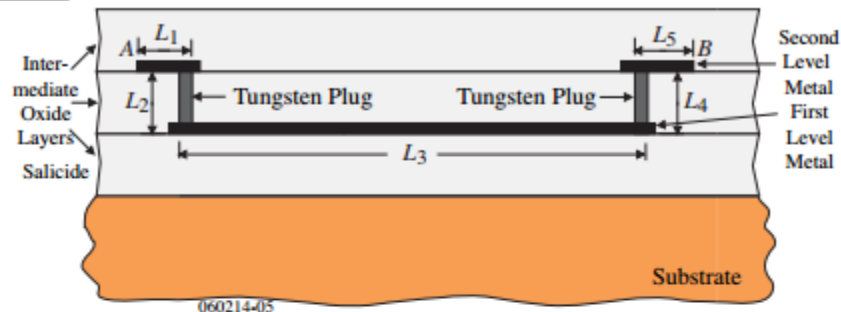
- Parasitic capacitance to substrate is voltage dependent.
- Piezoresistance effects occur due to chip strain from mounting.

Voltage and temperature dependence of R's

From lecture notes of Phil Allen

Metal as a Resistor

Illustration:



Resistance from A to B = Resistance of segments L_1 , L_2 , L_3 , L_4 , and L_5 with some correction subtracted because of corners.

Sheet resistance:

50-70 m Ω /□ \pm 30% for lower or middle levels of metal

30-40 m Ω /□ \pm 15% for top level metal

Watch out for the current limit for metal resistors.

Contact resistance varies from 5 Ω to 10 Ω .

Tempco \approx +4000 ppm/ $^{\circ}$ C

Need to derate the current at higher temperatures:

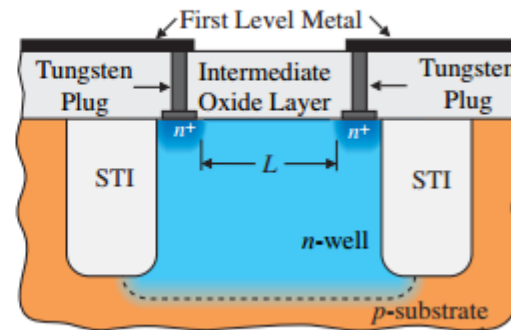
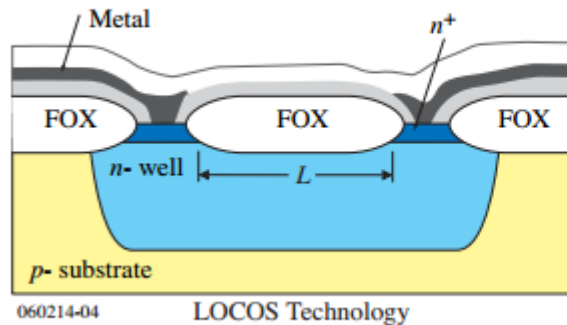
$$I_{DC}(T_j) = D_I I_{DC}(T_r)$$

$T_j(^{\circ}\text{C})$	$T_r(^{\circ}\text{C})$	D_I
<85	85	1
100	85	0.63
110	85	0.48
125	85	0.32
150	85	0.18

Voltage and temperature dependence of R's

From lecture notes of Phil Allen

N-well Resistor



1000-5000 ohms/square

Absolute accuracy = $\pm 40\%$

Relative accuracy $\approx 5\%$

Temperature coefficient = 4000 ppm/ $^{\circ}\text{C}$

Voltage coefficient is large ≈ 8000 ppm/V

Comments:

- Good when large values of resistance are needed.
- Parasitics are large and resistance is voltage dependent
- Could put a *p*⁺ diffusion into the well to form a pinched resistor

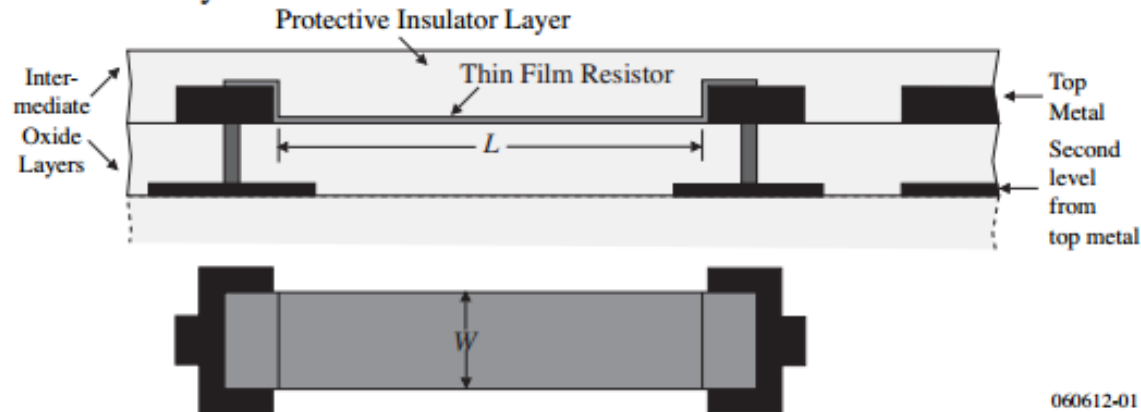
Voltage and temperature dependence of R's

From lecture notes of Phil Allen

Thin Film Resistors

A high-quality resistor fabricated from a thin nickel-chromium alloy or a silicon-chromium mixture.

Uppermost metal layer:



Performance:

Sheet resistivity is approximately 5-10 ohms/square

Temperature coefficients of less than 100 ppm/°C

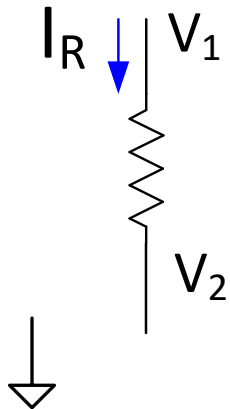
Absolute tolerance of better than $\pm 0.1\%$ using laser trimming

Selectivity of the metal etch must be sufficient to ensure the integrity of the thin-film resistor beneath the areas where metal is etched away.

060612-01

Voltage and temperature dependence of R's

Be careful with characterization of voltage coefficients of resistors –
simulators probably can not be completely trusted !



$$I_R = f_1(V_1 - V_2) \quad ?$$

$$I_R = f_2(V_1, V_2) \quad ?$$

$$R = ?$$

The Designer's Guide Community

downloaded from www.designers-guide.org

Modeling Diffusion Resistors

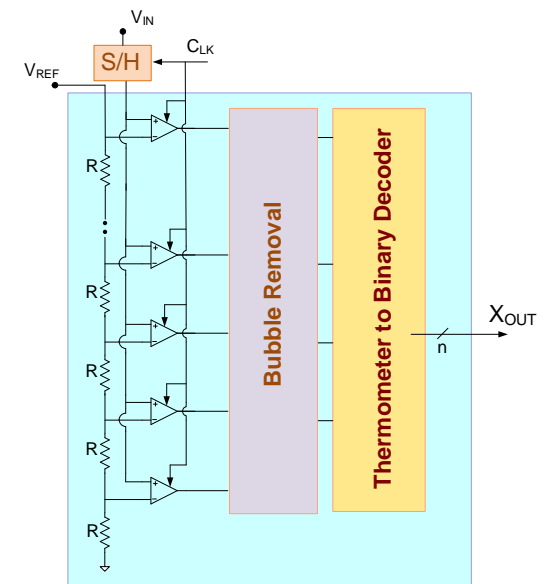
Ken Kundert

Designer's Guide Consulting, Inc.

The issues:

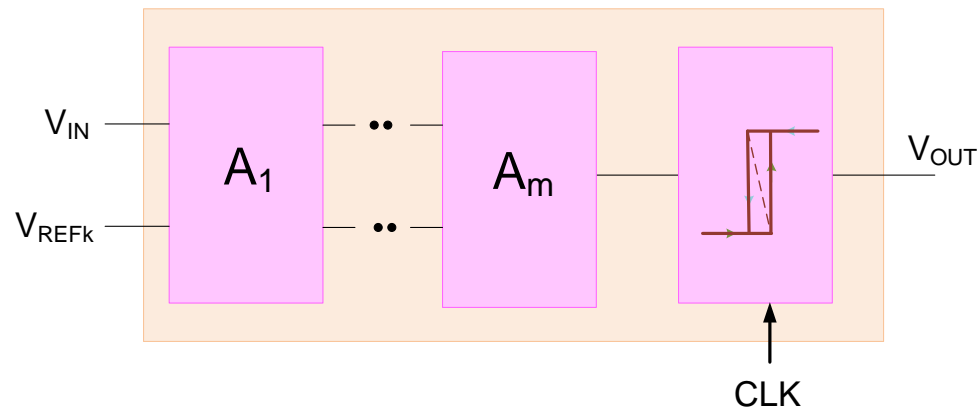
- How is resistance actually defined when I-V relationship is not linear
- Are integrated resistors 2-terminal or 3-terminal devices?

Interpolating ADC

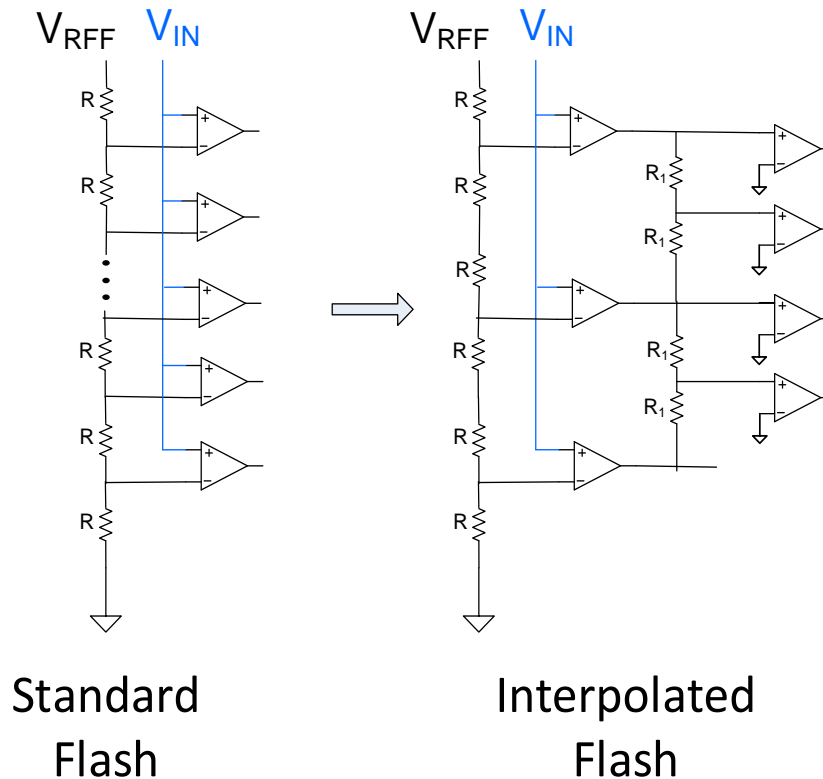


Full Flash ADC

- Key decisions being made by comparators near 0-1 thermometer code transition in Flash ADCs
- Other comparators (away from key decision region) consume power and area but provide little useful information
- Each regenerative comparator typically requires a preamp stage(s) in full flash ADC



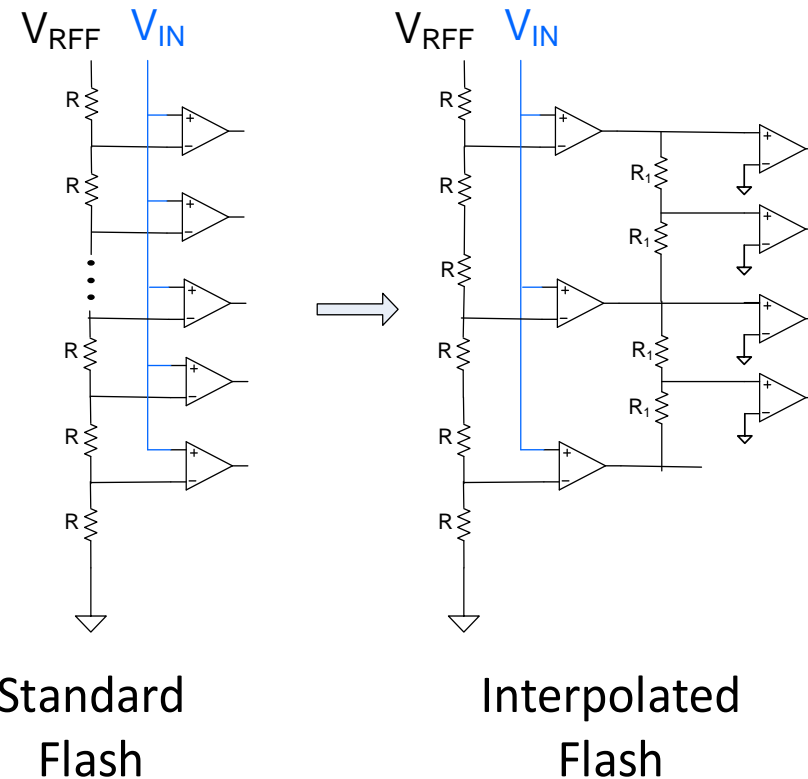
Interpolating Flash ADC



It may appear that the number of amplifiers/comparators and resistors have been increased but ...

- First stage amplifiers/comparators can be a pre-amp
- Second stage comparators can be a latch
- Number of critical resistors in first stage has been decreased (thereby also facilitating common-centroid layout)

Interpolating Flash ADC



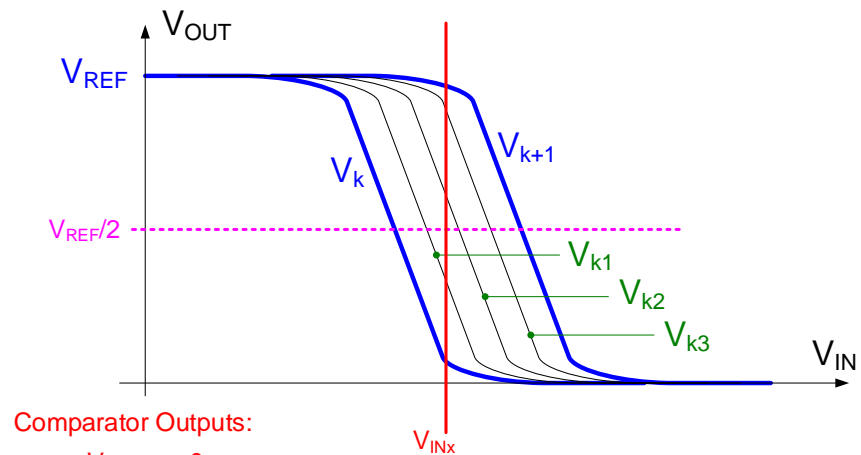
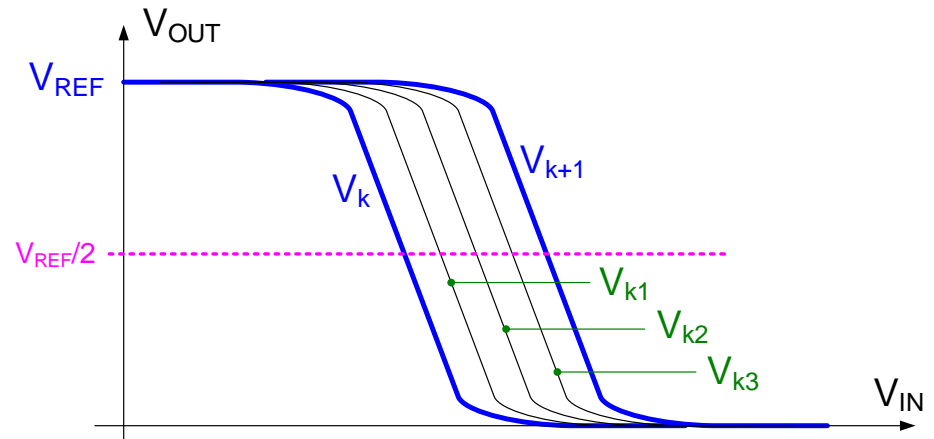
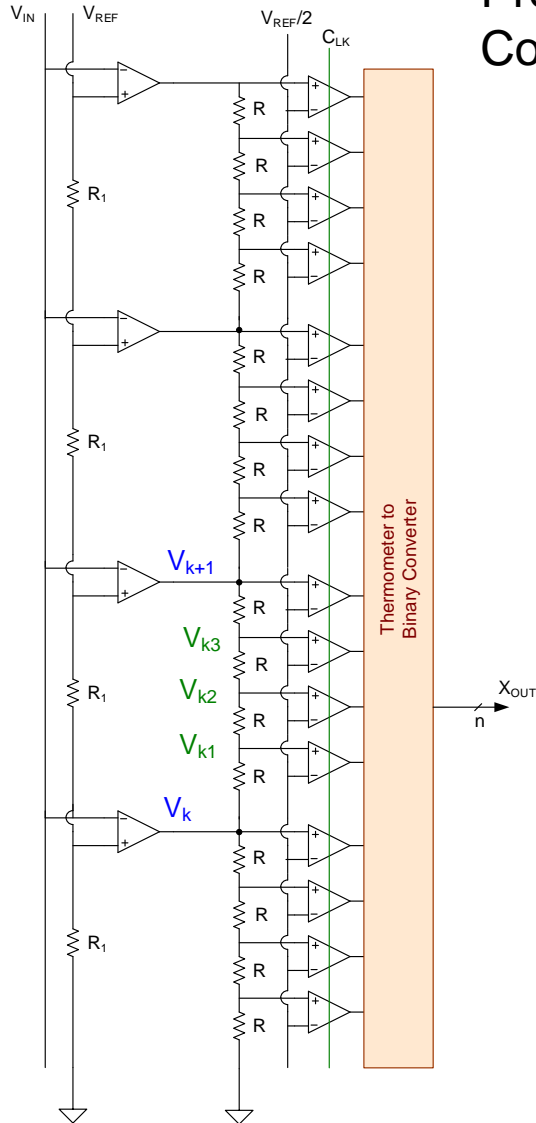
- Reduction in pre-amp area and power
- Latches all referenced to ground
- Loading on V_{IN} reduced
- Kickback to V_{REF} reduced
- V_{IN} coupling to V_{REF} reduced
- Multiple levels can be included in interpolator array

Interpolating Flash ADC

4 –levels of interpolation

Preamplifier gain not critical

Common mode set at $V_{REF}/2$



Comparator Outputs:

V_k	0
V_{k1}	0
V_{k2}	1
V_{k3}	1
V_{k+1}	1

V_{INx} line really is vertical !



Stay Safe and Stay Healthy !

End of Lecture 21